

## Publisher's Note: "Evolution of self-assembled type-II ZnTe/ZnSe nanostructures: Structural and electronic properties" [J. Appl. Phys. 111, 093524 (2012)]

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Citation: Journal of Applied Physics 112, 019902 (2012); doi: 10.1063/1.4736735

View online: http://dx.doi.org/10.1063/1.4736735

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(Received 9 May 2012; accepted 27 June 2012; published online 6 July 2012)

[http://dx.doi.org/10.1063/1.4736735]

This article was originally published online on 9 May 2012 with an error in author X. Q. Pan's name.

The author's name was correct in the printed version of the article. All online versions of the article were corrected on 11 May 2012.

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